Abstracts

A New Method for Measuring Properties of Dielectric Materials Using a Microstrip Cavity (Short Papers)

T. Itoh. "A New Method for Measuring Properties of Dielectric Materials Using a Microstrip Cavity (Short Papers)." 1974 Transactions on Microwave Theory and Techniques 22.5 (May 1974 [T-MTT]): 572-576.

A new nondestructive method has been developed for measuring the dielectric constant and the loss factor of a slab-type material using a microstrip cavity. The method, which uses a simple and rapid substitution procedure, yields accurate results and has a number of advantages over currently available techniques. Experimental details and the theoretical basis are explained and experimental data are presented.

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